

Special March 2004 Issue

This special issue of *Powder Diffraction* is dedicated to twenty of the highest quality papers presented at the 2003 Denver X-ray Conference. Publication of regular technical articles and new diffraction data will resume in the June 2004 issue.

In the June 2003 issue of *Powder Diffraction*, we reported that this journal and the Denver X-ray Conference agreed to a collaboration to better serve the subscribers of *Powder Diffraction* and attendees of the Denver X-ray Conference. This includes advance publications of both the Denver X-ray Conference program and selected advance articles from the proceedings of the Denver X-ray Conference (namely, *Advances in X-ray Analysis*) in *Powder Diffraction* annually. The subscribers of *Powder Diffraction* will also receive *Advances in X-ray Analysis* on CD-ROM.

The 52nd Annual Denver X-ray Conference was held in Denver, 4–8 August 2003, attracting over 500 attendees. The first two days of the Conference featured 16 tutorial workshops in X-ray and related fields. The remaining conference week was devoted to seventeen technical sessions. More than 220 papers covering a wide range of subjects in X-ray diffraction, X-ray fluorescence, and special topics in material characterization were presented at these sessions. Sixty of these papers have been accepted and

will be published in Volume 47 of *Advances in X-ray Analysis*.

The Denver X-ray Conference Organizing Committee has selected twenty of the highest quality papers from Volume 47 of *Advances in X-ray Analysis* for advance publication in this issue. The selected articles are grouped into six categories: X-ray Studies of Art and Archaeological Objects, Powder Diffraction Databases, Powder Diffraction Analysis, Thin Film Analysis, Texture and Stress Analysis, and X-ray Fluorescence Analysis.

We hope that this collaboration between *Powder Diffraction* and the Denver X-ray Conference will increase the exposure of the best in X-ray analysis to the broader X-ray community in general and to the subscribers of *Powder Diffraction* in particular.

We are grateful to Dr. Tim Fawcett, Executive Director of ICDD, for facilitating the collaboration between *Powder Diffraction* and the Denver X-ray Conference. Many thanks to the members of the Denver X-ray Conference Organizing Committee for reviewing and selecting the articles for this issue of *Powder Diffraction*. Finally, we thank also our authors for their scientific contributions and cooperation.

Ting C. Huang
Editor-in-Chief